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APPLICATION NO.

APPLICANT

Patrick P. Naulleau

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GROUP

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT09/94 S.391
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U.S. PATENT DOCUMENTS

Examiner Initials	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication (MM-DD-YYYY)
	Number	Kind Code (if known)		
AM	5,510,230		Tennant et al.	04-23-1996
AM	5,512,759		Sweatt	04-30-1996
AM	5,920,380		Sweatt	07-06-1999
AM	6,033,079		Hudyma	03-07-2000
AM	6,072,852		Hudyma	06-06-2000
AM	6,084,938		Hara et al.	07-04-2000
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AM	6,188,513		Hudyma	02-13-2001
AM	6,198,793		Schultz et al.	03-06-2001
AM	6,226,346		Hudyma	05-01-2001
AM	6,262,836		Hudyma et al.	07-17-2001

FOREIGN PATENT DOCUMENTS

Examiner Initials	Foreign Patent Document		Country	Date of Publication (MM-DD-YYYY)	Translation	
	Number	Kind Code (if known)			Yes	No

NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Include name of author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
AM	Naulleau, P. et al., "Characterization of the accuracy of EUV phase-shifting point diffraction interferometry", <i>SPIE</i> , vol. 3331, pp. 114-123
AM	White, D.L. et al., "Modification of the coherence of undulator radiation", <i>Rev. Sci. Instrum.</i> , 66 (2), Feb. 1995, pp. 1930-1933

Examiner Signature

Alan Mathews

Date Considered

8-7-2003

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. SEND TO: Assistant Commissioner for Patents, Washington, D.C. 20231.